

TECHNICAL FEATURES

SYSTEM DESCRIPTION

Computer

- * Pentium (current model) controller in a tower case
- * Large RAMBUS RAM or ECC RAM
- * Large format hard disk drive
- * DVD-RW/CD-ROM Drive, 3.5" Floppy Disk and ZIP Drive
- * 100 Mb Ethernet board
- * Keyboard, Serial Mouse, USB 2.0,
- * 17" Color Monitor
- * Beijert proprietary interfaces

Software

- * Microsoft Windows® NT / Windows® 2000 / XP
- * Microsoft Excel (Spreadsheet & Database)
- * BE Manager II executive system
- * BE System diagnostics
- * BE System calibration software
- * SPC Analysis Software

Measurement Center

- * All measurement electronics and I/O connections are contained in the system kiosk.
- * The measurement centre supports up to 10,000 channels but is supplied as standard with 960 channels .
- * Mechanics are mounted on a stable platform, both probe card and motherboards are mounted onto a comfortable "flip" table which rotates from left to the right position.
- * Temperature monitoring featuring TempAlarm during test and rework
- * Rework of probe card from the bottom position is facilitated by a flip table, coordinated camera tracking and image translation.

MEASUREMENT DESCRIPTION

more detailed information in the datasheet or see our website

Contact resistance	0-9 ohms, 1 milli ohm resolution
Leakage	0-300 nano-amps, 0,1 nano-amp
Planarity	travel 10 or 20 mm 0,1 micron resolution
Alignment	travel 12 X 8 inch (X & Y) 0,1 micron resolution
Gram Force	1-30 gram 0,1 gram resolution
Motherboards	up to 18 inch square

Options

- * Expandable PMU channel up to 10,000
- * Powerful Z stage lift to 100 Kg
- * Hot chuck / bussed probes, Relay control board
- * LCR components board
- * Microscope Leica / other configurations
- * N.I.S.T. calibration card
- * Ultra Low Leakage measurement Parametric probecards
- * RF Tag Inventory control system
- * Auto fine leveling for different probecard platforms

Operating Environment

Temperature	20-23 degrees centigrade (65-75 F.)
Humidity	30-50% RH
Mains voltage	120VAC 60 Hz or 220 VAC 50 Hz.

Weight and dimensions desk

Dimensions	165 X 90 X 180 CM (Height X Depth X Width) .
Weight	525 Kgs including PC and ancillaries



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Manager II is a registered trademark of Beijert Engineering.
All specifications are subject to change without notice.
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Manager II is manufactured by
Beijert Engineering Rev.09- 01.02
Patent pending

MANAGER II PROBE CARD VERIFICATION AND MANAGEMENT SYSTEM



BEIJERT probe card test solution
Engineer for the semiconductor industry



MANAGER SERIES II

PROBE CARD TESTER

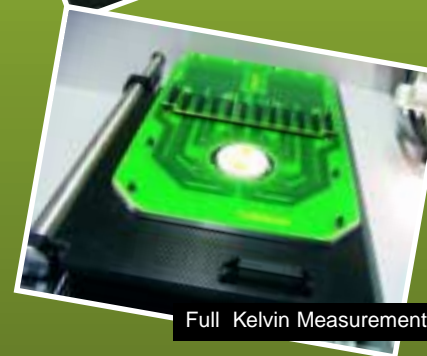
INTRODUCTION

Manager II is a probe card test and verification system that is used as a production tool for the verification of large complex probe cards before and after use and to facilitate rework of probe cards that do not conform to predefined standards. Manager II comprises a computer, specialized Windows® application software, a precision measurement subsystem, dual vision subsystem, precision motion subsystem and analysis software.

Manager II is intended for the measurement and adjustment of probe cards: planarization, XY location, probe tip analysis, probe pin to channel verification, probe contact resistance, leakage between probes, gram force and component measurement. All are standard in an easy-to-use automated test system.



Rework capability



Full Kelvin Measurement

CONTACT FORCE

MANAGER II offers two options to check the contact force (gram force). One measurement technique is to measure all probes in one movement and calculate the average value; the other technique is to measure each individual probe individually.

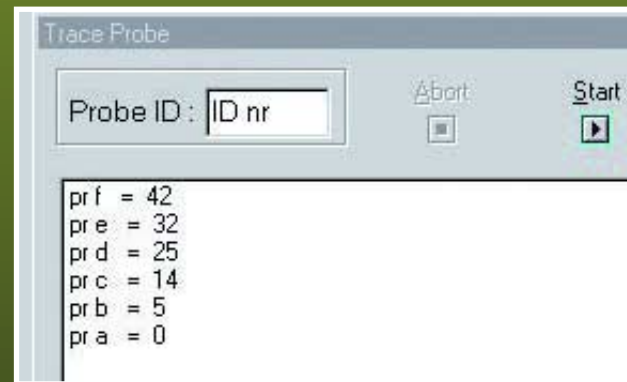


XY alignment view



GRAPHIC DISPLAY

MANAGER II provides a clear, easy to read display of individual probe parameters.

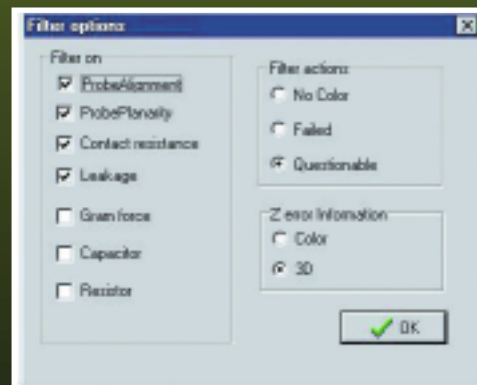


EASY OPERATING

Manager II has easy to use software; the operator selects which module they need. To make a new file for a new probecard "Trace Probe" may be used. This works with software to allow a new file to be quickly build. When the test is complete the software indicates pass/fail with a "traffic light icon. The system user is then able to repair defective cards with the current program which support easy repair functions.

TEST ELECTRICAL PARAMETERS

In addition to alignment and planarity, the system can measure contact resistance (including ultra low resistance) and compare the results against the stored reference data file. Probetips can be cleaned or sanded with the MANAGER II to allow for retest of contact resistance. Manager II has two user selectable leakage test modes one to check to adjacent probes the second to all tested probes. Bussed probes on a probecard can be analysed with the installed option in the system. Up to 10,000 channels can be checked.



WWW.PROBECARDTESTER.COM

OPTIONS



PMC boards



Other features

MANAGER AS A PRODUCTION TOOL

Although Manager II has considerable measurement and analytical capability, Manager II has been designed from the beginning to serve as a verification system. Its primary purpose is to ensure the integrity of probecard assemblies and verify that they are ready for test. SPC characterization before and after wafer sort will also allow analysis of probecard performance characteristics and facilitate correlation to test yield.

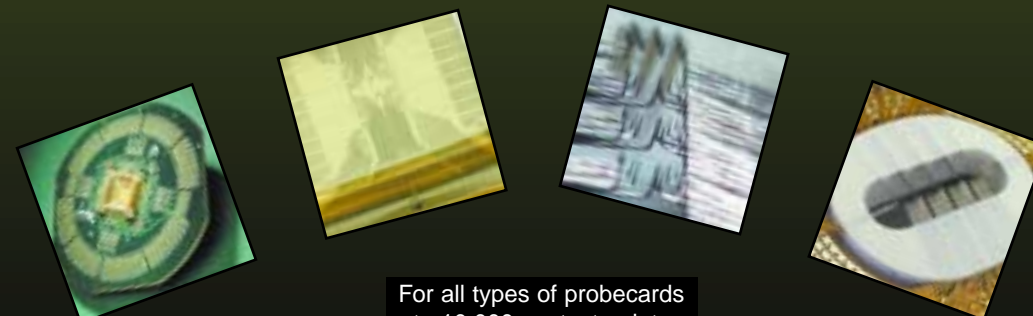
Chan	Card	Trace	Pad	X-ref.	Y-ref.	# Cross	Leak	Cross	Plan	Xerr	Yerr	
20	pr	1	PD5	w00	-3000	-2000	100	1	236	5	5	2
27	pr	2	PD9	x1	-3000	-3000	150	0	213	3	-2	4
5	pr	3	PD2	s2	-500	-750	200	1	198	6	1	2
3	bs	1	PD1	x3	10	10	250	1	210	-8	3	-5
22	bs	2	PD1	s4	1000	-2000	300	2	239	3	-4	-16
25	bs	9	PD2	d1	2000	3000	350	1	587	0	8	-19
26	bs	9	PD3	d2	-1000	100	400	1	137	2	-12	3
21	bs	10	PD4	gnd	1000	1500	450	1	149	1	2	8

CLEAR REPORTS

Manager II provides clear test reports in the universally familiar MS Excel format. The reports can be printed to the screen, as a file can be prepared for the Beijert "Analyst SPC" evaluation sent to a laser printer or uploaded via your network.

MANAGER II HIGHLIGHTS

- * Fully automated production verification
- * Allows large probecards for XY check
- * Neural software evaluation of probetip characteristic
- * Probecard flip table for easy rework
- * Motherboard with contact blocks for easy connections
- * Imports industry std data files
- * Server Attached Systems (SAS)



For all types of probecards to 10,000 contact points

MANAGER II - COMPLETELY AUTOMATED PROBE CARD VERIFICATION AND MANAGEMENT SYSTEM